

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977/279001/US5023/5025	Application No.
	Applicant Yamazaki, et al.		
	Filing Date June 25, 2001	Group Art Unit	

 903 U.S. PTO
09/892225


U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
M>	AA	5,643,826	7/1/97	Ohtani, et al.			
M>	AB	5,923,962	7/13/99	Ohtani, et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
M>	AL ✓	07-130652	5/19/95	Japan			Abstract only	
M>	AM ✓	08-078329	3/22/96	Japan			Abstract only	
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
M>	AQ ✓	Ishihara, et al., "Microtexture Analysis of Location Controlled Large Si Grain Formed by Excimer-Laser Crystallization Method", AM-LCD 99, Digest of Technical Papers, pp. 99-102, July 1999, Tokyo, Japan.
	AR	
	AS	
	AT	

Examiner Signature <i>Matthew Seng</i>	Date Considered 12/11/2002
EXAMINER: Initials Citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449

U.S. Department of Commerce
Patent and Trademark Office

Attorney's Docket No.

07977-279001

Application No.

09/892,225

**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

Applicant

Yamazaki, et al.

Filing Date

June 25, 2001

Group Art Unit

2811

U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
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	AC						
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	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
MS ↓	AQ ✓	U.S. Serial No. 09/874,204, filed June 6, 2001 entitled "Thin Film Transistors and Semiconductor Device", Specification 44 pages; 132 Claims; Abstract 1 page; Drawings 24 Figs.
	AR ✓	U.S. Serial No. 09/880,089, filed June 14, 2001 entitled "Semiconductor Device", Specification 65 pages; 50 Claims; Abstract 1 page; Drawings 45 Figs.
	AS ✓	U.S. Serial No. 09/882,265, filed June 18, 2001 entitled "Semiconductor Device", Specification 100 pages; 52 Claims; Abstract 1 page; Drawings 32 Figs.
	AT	

Examiner Signature

Matthew Song

Date Considered

12/12/2001

EXAMINER: Initials of person considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.